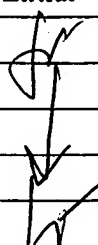


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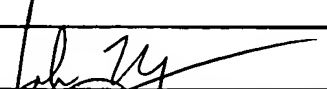
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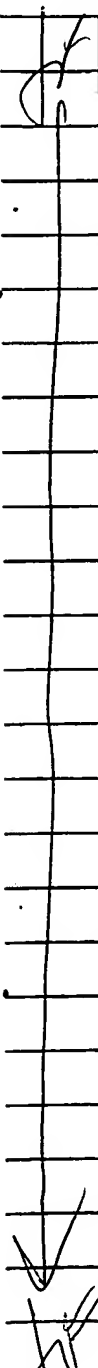
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	4,228,815	10/1980	Juffa et al.			
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JF	DE 2 934 566 A1	03/19/81	Germany	Abstract
JF	DE 32 34 146 A1	03/15/84	Germany	Abstract
JF	DE 42 22 458 A1	01/13/94	Germany	Abstract
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JF	Bonne et al., "Industrial Wireless PHASED Sensor Phase 1. Feasibility Demonstration," Progress Report for 4th Quarter of 2002, pp. 1-17, January 31, 2002.
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